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## What is claimed is:

1. A surface plasmon resonance measuring chip for use in a surface plasmon resonance measurement apparatus constituted of a light source for emitting a light beam; an optical system for making said light beam enter a dielectric block at various angles of incidence so that a condition for total internal reflection is satisfied at an interface between said dielectric block and said metal film; and photodetection means for detecting the intensity of said light beam satisfying total internal reflection at said interface to detect surface plasmon resonance; comprising:

a dielectric block;

a metal film, formed on a surface of said dielectric block, for placing a sample thereon;

wherein said dielectric block is formed as a single block that includes an entrance surface which said light beam enters, an exit surface from which said light beam emerges, and a surface on which said metal film is formed;

said metal film is united with said dielectric block; and

said dielectric block is formed from a synthetic resin in which, when said light beam is p-polarized outside said dielectric block and then strikes said interface, the intensity of an s-polarized component at said interface is 50% or less of the intensity of said light beam at said interface.

2. The surface plasmon resonance measuring chip as

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set forth in claim 1, wherein said dielectric block is formed from a synthetic resin in which, when said light beam is p-polarized outside said dielectric block and then strikes said interface, the intensity of a s-polarized component at said interface is 30% or less of the intensity of said light beam at said interface.

- 3. The surface plasmon resonance measuring chip as set forth in claim 1, wherein said dielectric block is formed from a synthetic resin in which, when said light beam is p-polarized outside said dielectric block and then strikes said interface, the intensity of a s-polarized component at said interface is 10% or less of the intensity of said light beam at said interface.
- 4. The surface plasmon resonance measuring chip as set forth in claim 1, wherein said synthetic resin is a synthetic resin that is selected from polymethylmethacrylate, a cycloolefin polymer, or a cycloolefin copolymer.
- 5. The surface plasmon resonance measuring chip as set forth in claim 2, wherein said synthetic resin is a synthetic resin that is selected from polymethylmethacrylate, a cycloolefin polymer, or a cycloolefin copolymer.
- 6. The surface plasmon resonance measuring chip as set forth in claim 3, wherein said synthetic resin is a synthetic resin that is selected from polymethylmethacrylate, a cycloolefin polymer, or a cycloolefin copolymer.
- 7. The surface plasmon resonance measuring chip as set forth in claim 1, wherein a sensing medium that exhibits a coupling reaction with a specific substance in said sample

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is fixed on said metal film.

- 8. The surface plasmon resonance measuring chip as set forth in claim 2, wherein a sensing medium that exhibits a coupling reaction with a specific substance in said sample is fixed on said metal film.
- 9. The surface plasmon resonance measuring chip as set forth in claim 3, wherein a sensing medium that exhibits a coupling reaction with a specific substance in said sample is fixed on said metal film.
- 10. The surface plasmon resonance measuring chip as set forth in claim 4, wherein a sensing medium that exhibits a coupling reaction with a specific substance in said sample is fixed on said metal film.
- 11. The surface plasmon resonance measuring chip as set forth in claim 5, wherein a sensing medium that exhibits a coupling reaction with a specific substance in said sample is fixed on said metal film.
- 12. The surface plasmon resonance measuring chip as set forth in claim 6, wherein a sensing medium that exhibits a coupling reaction with a specific substance in said sample is fixed on said metal film.
- 13. A method of manufacturing a surface plasmon resonance measuring chip for use in a surface plasmon resonance measurement apparatus constituted of
- a light source for emitting a light beam;
  an optical system for making said light beam enter a

dielectric block at various angles of incidence so that a condition for total internal reflection is satisfied at an interface between said dielectric block and said metal film; and

photodetection means for detecting the intensity of said light beam satisfying total internal reflection at said interface to detect surface plasmon resonance;

wherein said dielectric block is formed as a single block that includes an entrance surface which said light beam enters, an exit surface from which said light beam emerges, and a surface on which said metal film is formed; comprising the step of:

manufacturing the measuring chip with said dielectric block being formed integrally with said metal film by positioning a resin introducing gate in a position that faces the surface of the mold that defines the surface on which said metal film is to be formed and forming said block by injection molding.